



ADVANCED ELECTRONICS LABORATORIES



WORKSHOP ON CHIP PROCESS DESIGN & ANALYTICAL TESTING

In continuation to the previous workshops, Advanced Electronics Laboratories offer a 6-days workshop on **CHIP PROCESS DESIGN AND ANALYTICAL TESTING** for all of its graduate students who are entering into research phase from FALL 2016. The lab engineers and faculty members from Faculty of Engineering & Technology, Faculty of Basic and Applied Sciences and Iqra College are also encouraged to attend the workshop to gain the knowledge of technological processes of IC design as well as post-process reliability, efficiency and failure analysis of devices and nano-systems. The training will be conducted on internationally licensed softwares and R&D grade sophisticated machines in the laboratories.

Day 1 & Day 2:

Introduction to State of the art
Licenced tools

- Why Device Design is phenomenally important?
- CMOS Scaling & Efficiency, IC Fabspecific design and processes
- Road to technology files, ATHENA, ATLAS, BLAZE, LUMINOUS, ORGAN

Day 3 & Day 4:

Advanced Electrical/Electro-
Optical Characterizations

- Nano chip reliability grade Hall Effect Chip level Characterizations
- Multi-head Probe station assembeled with varaiety of different device/circuit level techniques
- Introduction to van der paw, Hall and Clover leaf patterens for Hall Analysis
- Effect of Magnitization, Electric Field, Transient of bais sweeps, Resistivity/Conductivity Scans, Charge Carrier Cocentrations, Electron/Hole Mobilities for Chip level assesment
- Practical hands on Open Circuit Voltage (Voc) and Short Circuit Current (Isc) for PV devices
- Effect of Current Voltage (I-V) and Capcitanace Voltage (C-V) profiling for research prospects
- Introduction to very sophisticated characterization techniques; Charge Deep Level Transient Spectroscopy (Q-DLTS) and Photo stimulated Internal Field Transient Spectroscopy
- Issues in device reliability

Day 5:

Optical Assessment & Rapid
Thermal Processing

- Optical profilometry and scanning of optical parameters like refractive index, dielectrics, extinction coefficients, thickness at subnano scales
- Optical Characterization of Si based Quadrant photo detector (basic overview)
- Hands on with multiple devices and samples, working out the electro-optics
- Experimentation on Rapid thermal annealing machine, Technique of RT-CVD, RTO and RTP, ITRS specific Thermal budget

Day 6:

Back End Processes

- Device's Metalization, Cleaning, Etching, Spin Coating, Baking.
- Wet chemistry, contact development, Physical Layer Depostion, packaging etc.

AELP HIGHLIGHTS

- State of the art Device Design and Process Characterization Facilities under one roof
- Over 85 running scientific projects besides over 300 of Quality Assurance runs
- Problem converging on the forefronts of Micro & Nano Electronics, Photonics & Optoelectronics, Photovoltaic Engineering & Energy and Sensing & Detection
- 34% of the total running projects are from outside the IIUI including other universities, industry and national scientific organizations

Days: 24th to 29th Oct., 2016

Time: 10:00 AM – 4:00 PM

Venue:

**Advanced Electronics Laboratories, Ibn-
Khaldun Block, IIUI**

For Confirmation and Queries

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